# INFRARED SPECTROSCOPIC STUDY AND CHARACTERISTICS OF SnO<sub>2</sub>-BASED THICK FILM FOR CH<sub>3</sub>CN DETECTION

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**Abstract** – The SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film devices were fabricated by screen printing and dipping methods, and their sensing characteristics to CH<sub>3</sub>CN gas was investigated. The oxidation products of CH<sub>3</sub>CN on the thick film were analyzed by FT-IR using a heatable gas cell. The IR results showed that the products formed by oxidation of CH<sub>3</sub>CN at 300 °C on the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> thick film without SiO<sub>2</sub> were mainly CO<sub>2</sub>, H<sub>2</sub>O, and NH<sub>3</sub>, while on the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film products such as CO<sub>2</sub>, H<sub>2</sub>O, N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> were observed. The thick film devices containing SiO<sub>2</sub> showed high selectivity and negative sensitivity to CH<sub>3</sub>CN due to the presence of nitrogen compounds produced by oxidation of CH<sub>3</sub>CN. Optimum amount of Nb<sub>2</sub>O<sub>5</sub> and operating temperature were 1. 0 wt% and 300 °C, respectively.

Key words: Oxidation of CH<sub>3</sub>CN, SnO<sub>2</sub>-based Sensor, FT-IR Spectra, Dipping of Si(C<sub>2</sub>H<sub>5</sub>O)<sub>4</sub>, Negative Sensitivity

# **INTRODUCTION**

Semiconductor gas sensors using  $\text{SnO}_2$  and ZnO have been studied extensively since they were proposed by Seiyama et al. [1962]. These oxide gas sensors can detect various gases based the conductivity changes of their surface due to the adsorption and desorption of gases.

Successively, several research laboratories worked with the aim of developing new devices. The most recent research on flammable gas sensors has concentrated on  $\text{SnO}_2$  in the form of thick-film and sintered ceramics [Lee et al., 1987; Torvela et al., 1988; Egashira et al., 1986]. The working mechanism of thick-film and sintered gas sensors is based on the build up of Schottky barriers between adjacent grains caused by the ionosorbed oxygen [McAleer et al., 1988].

The sensors show many advantages over optical or electrochemical sensors. The main advantages are their low cost, low consumption of electrical power, and high sensitivity. However, they should be improved due to a lack of stability and a poor selectivity.

An improvement of the selectivity of sensors based on  $\text{SnO}_2$ is generally obtained by adding some specific catalysts such as Pd or Pt for heavy combustible gases [Torvela et al., 1991; Fryberger and Semancik, 1990; Klober et al., 1991], Bi<sub>2</sub>O<sub>3</sub> for hydrogen [Sberveglieri et al., 1992], and ThO<sub>2</sub> for CO [Nitta and Haradome, 1979].

In this work, we have developed tin oxide-based thick film sensor for detection of acetonitrile gas which is known to be a poisonous chemical at low level in air. The sensing characteristics of  $SnO_2$ -based sensor to acetonitrile were studied by FT-IR analyses of gaseous species produced by oxidation of CH<sub>3</sub>CN on the surface of sensor.

#### **EXPERIMENTAL**

 $Al_2O_3$  (10.0 wt%) and  $Nb_2O_5$  (0.2-2.0 wt%) were mixed mechanically with the base material,  $SnO_2$ , followed by calcination in air at 600 °C for 1 hr. The calcined sample was ground and then mixed with water to prepare paste. The paste was screen-printed onto an alumina substrate and then dipped into tetraethylorthosilicate solution followed by sintering in air at 700 °C for 1 hr. Fabrication flow chart of thick film



Fig. 1. Fabrication flow chart of thick film sensor.

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sensor for the detection of CH<sub>3</sub>CN is given in Fig. 1. The sensor sensitivity was measured in a stainless box equipped with a heater, as described in a preceding publication [Park et al., 1993]. The sensitivity is defined as  $R_g/R_0$ , where  $R_0$  and  $R_g$  are the electric resistances in fresh air and in the test gas, respectively. The products formed by reaction of CH<sub>3</sub>CN on the surface of the sensor were analyzed by a Mattson Model GL 6030E FT-IR spectrometer using a heatable IR gas cell. FT-IR absorption spectra were measured over the range of 4,000-400 cm<sup>-1</sup>.

#### **RESULTS AND DISCUSSION**

The optimum base material was selected based on the oxidation decomposition temperature of CH<sub>3</sub>CN on the surface of various metal oxide and on the FT-IR analyses of the decomposed products. The decomposition reaction was carried out in a heatable gas IR cell under the condition of 20 torr CH<sub>3</sub>CN and 500 torr air. The decomposition temperature of CH<sub>3</sub>CN on metal oxides and their surface areas are listed in Table 1. On the surface of SnO<sub>2</sub>, CH<sub>3</sub>CN began to decompose at 130 °C and a lot of products were produced at 300 °C. The products from the decomposition reaction were H<sub>2</sub>O, NH<sub>3</sub>, CO<sub>2</sub>, and N<sub>2</sub>O. The easiness of decomposition on the surfaces of metal oxides falls in sequence:

$$SnO_2 > WO_3 > CoO > Fe_2O_3 > ZnO$$

Fig. 2 shows the IR spectra of  $CH_3CN$  (16 torr) and the oxidation products of  $CH_3CN$  on  $SnO_2$  thick film under the condition of  $CH_3CN$  16 torr and air 16 torr at 300 °C for 0.5 hr. For pure  $CH_3CN$ , the bands at 2,967 and 2,940 cm<sup>-1</sup> are assigned to  $CH_3$  stretching vibration mode, while those at 1,444 and 1381 cm<sup>-1</sup> are ascribed to the  $CH_3$  deformation [Knoezinger and Krietenbrink, 1975]. The bands at 2,299 and 2,260 cm<sup>-1</sup> are responsible for the CN group. However, on the SnO<sub>2</sub>, the bands due to  $NH_3$  and  $CO_2$  in addition to  $CH_3CN$  were observed as shown in Fig. 2. The bands at 3,414, 1,624, 964, and 930 cm<sup>-1</sup> are ascribed to the  $NH_3$ , while those at 3,723, 3,635, 2,361, and 667 cm<sup>-1</sup> are due to the  $CO_2$ . Oxidation of  $CH_3CN$  on  $SnO_2$  seems to proceed by the following reaction.

$$CH_3CN + 2O_2 = NH_3 + 2CO_2 \tag{1}$$

Fig. 3 shows IR spectra of oxidation products of CH<sub>3</sub>CN on  $SnO_2/Al_2O_3/Nb_2O_5$  and  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  at 300 °C for 0.5 hr. On  $SnO_2/Al_2O_3/Nb_2O_5$ , the bands (3,723, 3,635, 2,361,

Table 1. Decomposition temperature of CH<sub>3</sub>CN on metal oxides and their specific surface area

Metal oxide	Туре	Decomposition temperature (°C)	Surface area (m <sup>2</sup> /g)
SnO <sub>2</sub>	n	130	5.0
WO <sub>3</sub>	n	150	4.4
CoO	р	200-220	4.5
TiO <sub>2</sub>	n	230	6.1
Fe <sub>2</sub> O <sub>3</sub>	<b>n</b> .	250	3.0
ZnO	n	>300	4.8



Fig. 2. Infrared spectra of CH<sub>3</sub>CN and the oxidation reaction products of CH<sub>3</sub>CN on SnO<sub>2</sub> thick film.

667 cm<sup>-1</sup>) due to CO<sub>2</sub> and the bands (3,414, 3,334, 964, 930 cm<sup>-1</sup>) due to NH<sub>3</sub> were observed similarly to the case of SnO<sub>2</sub> in Fig. 2. However, on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film added with SiO<sub>2</sub>, N<sub>2</sub>O bands instead of NH<sub>3</sub> bands appeared at 2,238, 2,211, and 1,300 cm<sup>-1</sup> [Nakamoto, 1997]. Also, the bands due the formation of nitrate or nitrite ions were observed at 1,381 and 1,358 cm<sup>-1</sup> [Nakamoto, 1997]. N<sub>2</sub>O seems to form by the oxidation of NH<sub>3</sub> produced by Eq. (1) as the follows.

$$2NH_3 + 2O_2 = N_2O + 3H_2O$$
 (2)

Also, for the IR absorption bands due to nitrate and nitrite groups, the following reaction is assumed to occur [Fonster and Lesine, 1978]

$$2NO_2 + H_2O = HNO_3 + HNO_2$$
(3)

Oxidation of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> thick film produced NH<sub>3</sub>, as shown in Fig. 3. NH<sub>3</sub> oxidation was carried out in a gas cell to examine the behavior of NH<sub>3</sub> produced on the thick film, where the concentrations of NH<sub>3</sub> and air were 20 torr and 300 torr, respectively. The results are illustrated in Fig. 4. After reaction of NH<sub>3</sub> on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub> at 300 °C for 1 hr, other products except NH<sub>3</sub> were not detected, while at 350 °C the bands of H<sub>2</sub>O (3,450 and 1,587 cm<sup>-1</sup>) and N<sub>2</sub>O (2,238, 2,211, doublet and 1,300, 1,273 cm<sup>-1</sup> doublet) appeared. These results indicate that NH<sub>3</sub> is oxidized by the above Eq. (2) and the reaction occurs at 350 °C higher than 300 °C.

On the other hand, oxidation of NH<sub>3</sub> on  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  proceeded very easily even at 300 °C, as shown in Fig.



Fig. 3. Infrared spectra after oxidation reaction of  $CH_3CN$  on  $SnO_2/Al_2O_3/Nb_2O_5$  (a) and  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  (b) at 300 °C for 0.5 hr.



Fig. 4. Infrared spectra after oxidation reaction of  $NH_3$  on  $SnO_2/Al_2O_3/Nb_2O_5$  (a, b) and  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  (c).

4(c). Considering that the operating temperature of sensor is  $300 \,^{\circ}$ C, it is expected that addition of  $SiO_2$  gives a significant effect on the characteristics and sensing selectivity of  $SnO_2$ 

sensor.

Specific surface areas of some samples are listed in Table 2. The surface area of  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  is remarkably large compared to the other samples. It seems likely that the surface area also influences the sensing characteristics of sensor.

Fig. 5 shows infrared spectra of gases obtained by oxidation of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> at various temperatures for 0.5 hr, where the concentrations of CH<sub>3</sub>CN and air are 20 torr and 300 torr, respectively. From room temperature to 160 °C, no bands except that of CH<sub>3</sub>CN were observed, indicating that oxidation of CH<sub>3</sub>CN did not occur. At 240 °C, bands due to CO<sub>2</sub> (2,361 cm<sup>-1</sup>), N<sub>2</sub>O (2,238, 2,211 cm<sup>-1</sup>), HNO<sub>3</sub> (1,381 cm<sup>-1</sup>), and HNO<sub>2</sub> (1,358 cm<sup>-1</sup>) appeared and their intensities increased with reaction temperature as shown in Fig. 5. It is known that NH<sub>3</sub>, CO<sub>2</sub>, and H<sub>2</sub>O increase the electric conductivity of sensor, while N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> decrease the conductivity [Park et al., 1993]. Therefore, from the IR results of Fig. 5, it is clear that the SiO<sub>2</sub> component plays a great role in determining the detection limit of sensor.

Table 2. Specific surface areas of some samples

Sample	Surface area (m <sup>2</sup> /g)
SnO <sub>2</sub>	5.0
$SnO_2/Al_2O_3/Nb_2O_5$	22.0
SnO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /Nb <sub>2</sub> O <sub>5</sub> /SiO <sub>2</sub>	84.6



Fig. 5. Infrared spectra after oxidation reaction of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> at various temperatures for 0.5 hr.

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Fig. 6. Sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device as a function of Nb<sub>2</sub>O<sub>5</sub> content at 300 °C.



Fig. 7. Sensitivity of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device to CH<sub>3</sub>CN at various operating temperatures.

We examined the dependence of  $N_2O_5$  level (0.2-2.0 wt%) on the sensitivity of  $SnO_2/Al_2O_3/Nb_2O_3/SiO_2$  sensor, when the concentration of CH<sub>3</sub>CN was 17 ppm and the operating temperature was 300 °C. The  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  devices showed the negative sensitivity by increasing the resistance to CH<sub>3</sub>-CN, while the  $SnO_2/Al_2O_3/Nb_2O_5$  devices without SiO<sub>2</sub> exhibited the positive sensitivity to CH<sub>3</sub>CN. As shown in Fig. 6, the devices gave the highest sensitivity to 1.0 wt% N<sub>2</sub>O<sub>5</sub>, showing the increased resistance 22-35 times higher than for the



Fig. 8. Resistance characteristics of the SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> thick film device to various gases at 300 °C.



devices with different content of Nb<sub>2</sub>O<sub>5</sub> contents.

The sensing characteristics of  $\text{SnO}_2/\text{Al}_2\text{O}_3/\text{Nb}_2\text{O}_5/\text{SiO}_2$  device are illustrated as a function of CH<sub>3</sub>CN concentration at various operating temperatures in Fig. 7. The sensitivity increased with increasing the concentration of CH<sub>3</sub>CN and the optimum operating temperature was 300 °C. It seems likely that the decreased sensitivity at 350 °C is responsible for the large formation of nitrogen compounds such as N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> which decrease the electric conductivity, as shown in Fig. 5 [Park et al., 1993].

Fig. 8 shows sensing characteristic of  $SnO_2/Al_2O_3/Nb_2O_5/SiO_2$  device to various gases at the operating temperature of 300 °C. The device exhibited the positive characteristic of decreasing the resistance to CO, NO<sub>2</sub>, C<sub>4</sub>H<sub>10</sub> and C<sub>2</sub>H<sub>5</sub>OH, while the device exhibited negative characteristic of increasing the resistance to CH<sub>3</sub>CN and SO<sub>2</sub>. These results are in good agreement with the fact that, as shown in Fig. 3, SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> produce N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> which decrease the electric conductivity of sensor [Park et al., 1993]. Therefore, the gas sensor shows high sensitivity and selectivity to CH<sub>3</sub>CN.

Fig. 9 shows the response characteristics of the sensor to  $CH_3CN$ . The sensor was very sensitive to low gas concentration and the gas sensitivity tended to saturate in the range of high concentration (100 ppm). Also the sensor showed excellent recovery characteristics as the operating temperature increased. These results indicate that the response characteristics and sensitivity depend on the operating temperature. At 300 °C, the response and recovery times are 3 sec and 10 min, respectively.

#### CONCLUSIONS

The SnO<sub>2</sub>-based thick film devices for the detection of CH<sub>3</sub>-CN were fabricated by the screen printing and dipping methods. The oxidation products of CH<sub>3</sub>CN on SnO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub>/Nb<sub>2</sub>O<sub>5</sub>/ SiO<sub>2</sub> thick film were CO<sub>2</sub>, H<sub>2</sub>O, N<sub>2</sub>O, HNO<sub>3</sub> and HNO<sub>2</sub>. The oxidizing agents such as N<sub>2</sub>O, HNO<sub>3</sub>, and HNO<sub>2</sub> formed by oxidation of CH<sub>3</sub>CN played an important role in determining sensitivity and selectivity to CH<sub>3</sub>CN gas. The response time and the optimum operating temperature were 3 sec and 300 °C, respectively.

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